OptiMOS™ Power-MOSFET

Features

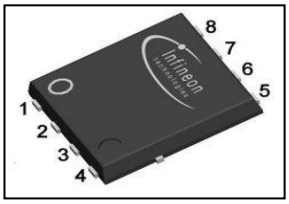
- Optimized for high performance SMPS, e.g. sync. rec.
- Very low on-resistance $R_{DS(on)}$ @ V_{GS}=4.5 V
- 100% avalanche tested
- Superior thermal resistance
- N-channel
- Qualified according to JEDEC[1] for target applications
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

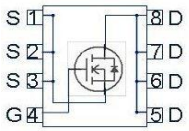
Pb-Free RoHS Halogen-Free

Product Summary

V_{DS}	40	V
$R_{DS(on),max}$	2.2	mΩ
I_D	100	A
Q_{OSS}	33	nC
Q_G(0V..10V)	37	nC

PG-TDSON-8





Type	Package	Marking
BSC022N04LS	PG-TDSON-8	022N04LS

Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I_D	V_{GS}=10 V, T_C=25 °C	100	A
		V_{GS}=10 V, T_C=100 °C	85	
		V_{GS}=4.5 V, T_C=25 °C	100	
		V_{GS}=4.5 V, T_C=100 °C	70	
		V_{GS}=10 V, T_A=25 °C, R_{thJA}=50 K/W[2]	25	
Pulsed drain current[3]	$I_{D,pulse}$	T_C=25 °C	400	
Avalanche current, single pulse	I_{AS}	T_C=25 °C	50	
Avalanche energy, single pulse[4]	E_{AS}	I_D=50 A, R_{GS}=25 Ω	70	mJ
Gate source voltage	V_{GS}		±20	V

[1] J-STD20 and JESD22

[2] Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

[3] See figure 3 for more detailed information

[4] See figure 13 for more detailed information

Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Power dissipation	P_{tot}	T_C=25 °C	69	W
		T_A=25 °C, R_{thJA}=50 K/W[2)]	2.5	
Operating and storage temperature	T_j, T_{stg}		-55 ... 150	°C
IEC climatic category; DIN IEC 68-1			55/150/56	

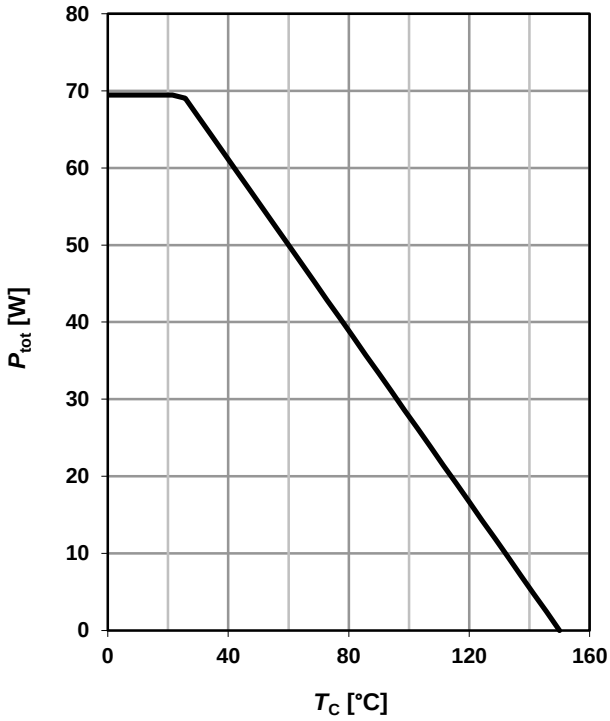
Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R_{thJC}		-	-	1.8	K/W
		top	-	-	20	
Device on PCB	R_{thJA}	6 cm^2 cooling area[2)]	-	-	50	
Electrical characteristics, at T_j=25 °C, unless otherwise specified						
Static characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}=0 V, I_D=1 mA	40	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_D=250 µA	1.2	-	2	
Zero gate voltage drain current	I_{DSS}	V_{DS}=40 V, V_{GS}=0 V, T_j=25 °C	-	0.1	1	µA
		V_{DS}=40 V, V_{GS}=0 V, T_j=125 °C	-	10	100	
Gate-source leakage current	I_{GSS}	V_{GS}=20 V, V_{DS}=0 V	-	10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V_{GS}=4.5 V, I_D=50 A	-	2.3	3.2	mΩ
		V_{GS}=10 V, I_D=50 A	-	1.8	2.2	
Gate resistance	R_G		-	1.1	-	Ω
Transconductance	g_{fs}	$\|V_{DS}\|>2\|I_D\|R_{DS(on)max}$, I_D=50 A	90	180	-	S

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C_{iss}	V_{GS}=0 V, V_{DS}=20 V, f=1 MHz	-	2600	-	pF
Output capacitance	C_{oss}		-	750	-	
Reverse transfer capacitance	C_{rss}		-	60	-	
Turn-on delay time	$t_{d(on)}$	V_{DD}=20 V, V_{GS}=10 V, I_D=50 A, $R_{G,ext}$=1.6 Ω	-	6.1	-	ns
Rise time	t_r		-	6.8	-	
Turn-off delay time	$t_{d(off)}$		-	26	-	
Fall time	t_f		-	5.0	-	
Gate Charge Characteristics[5]						
Gate to source charge	Q_{gs}	V_{DD}=20 V, I_D=50 A, V_{GS}=0 to 10 V	-	6.8	-	nC
Gate charge at threshold	$Q_{g(th)}$		-	4.2	-	
Gate to drain charge	Q_{gd}		-	6.0	-	
Switching charge	Q_{sw}		-	8.7	-	
Gate charge total	Q_g		-	37	-	
Gate plateau voltage	$V_{plateau}$		-	2.6	-	V
Gate charge total	Q_g	V_{DD}=20 V, I_D=50 A, V_{GS}=0 to 4.5 V	-	19	-	nC
Gate charge total, sync. FET	$Q_{g(sync)}$	V_{DS}=0.1 V, V_{GS}=0 to 4.5 V	-	15	-	
Output charge	Q_{oss}	V_{DD}=20 V, V_{GS}=0 V	-	33	-	
Reverse Diode						
Diode continuous forward current	I_S	T_C=25 °C	-	-	69	A
Diode pulse current	$I_{S,pulse}$		-	-	400	
Diode forward voltage	V_{SD}	V_{GS}=0 V, I_F=50 A, T_j=25 °C	-	0.85	1	V
Reverse recovery time	t_{rr}	V_R=20 V, I_F=50A, di_F/dt =400 A/µs	-	20		ns
Reverse recovery charge	Q_{rr}		-	36	-	nC

[5] See figure 16 for gate charge parameter definition

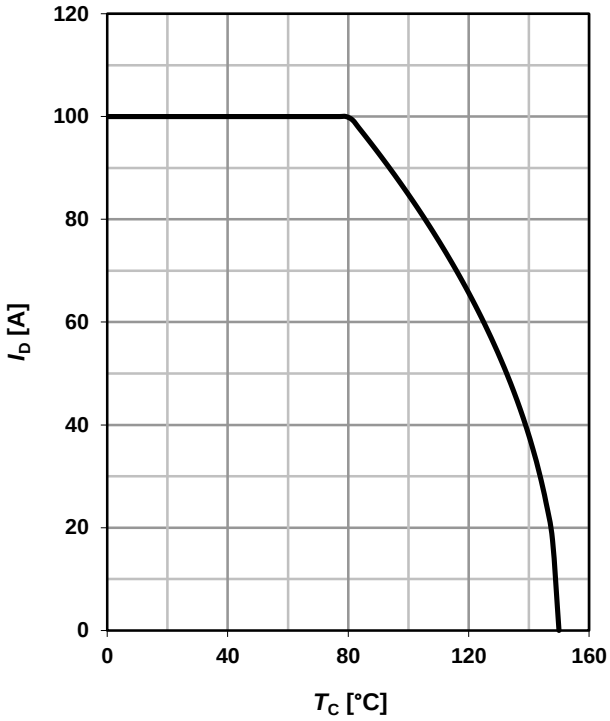
1 Power dissipation

$P_{tot}=f(T_C)$



2 Drain current

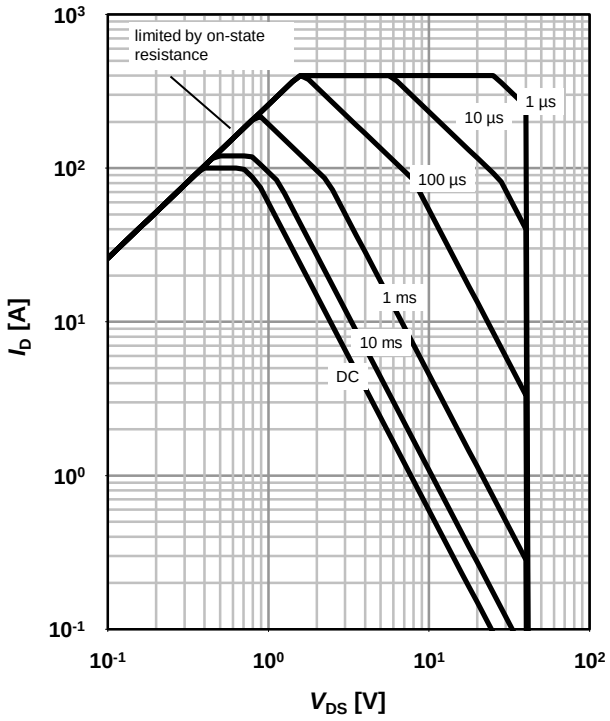
$I_D=f(T_C)$; $V_{GS}\geq 10$ V



3 Safe operating area

$I_D=f(V_{DS})$; $T_C=25$ °C; $D=0$

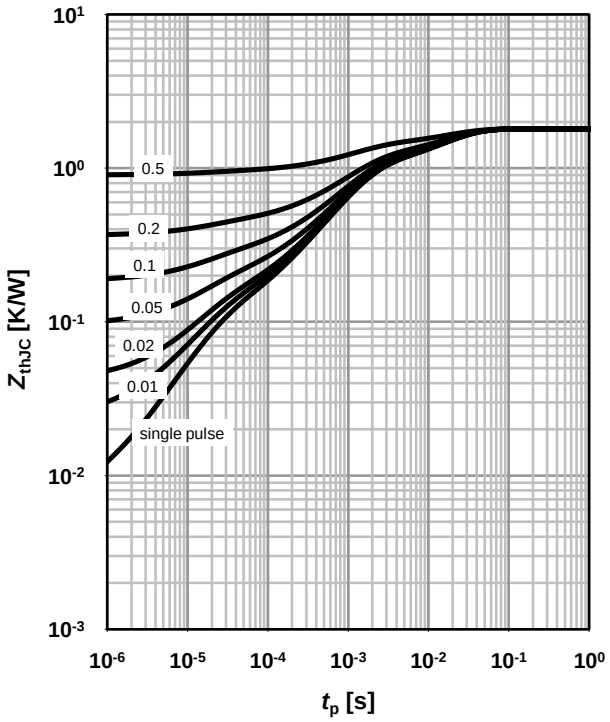
parameter: t_p



4 Max. transient thermal impedance

$Z_{thJC}=f(t_p)$

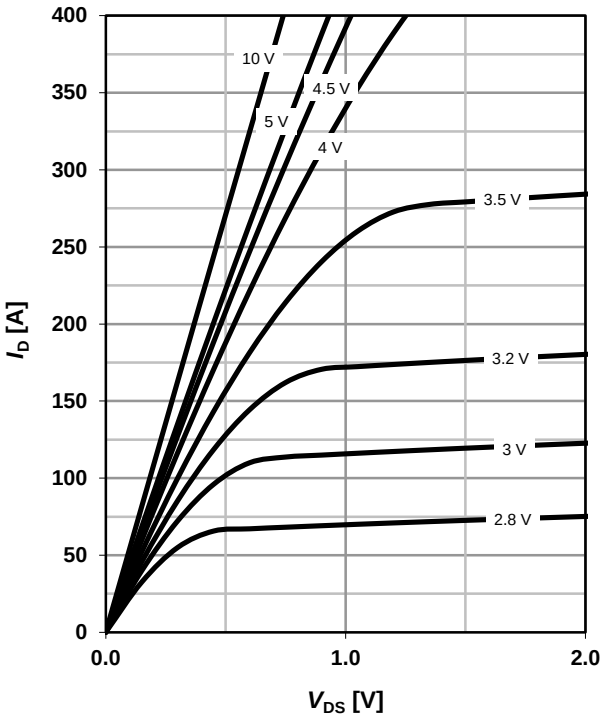
parameter: $D=t_p/T$



5 Typ. output characteristics

$I_D=f(V_{DS})$; $T_j=25$ °C

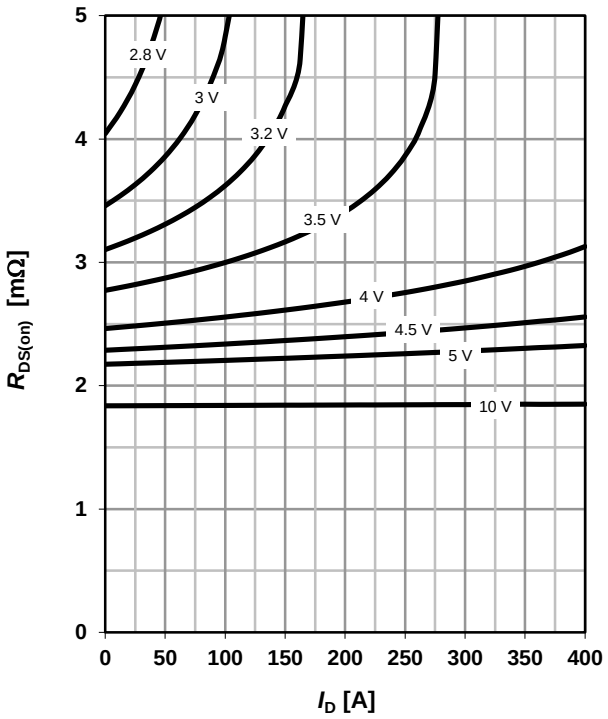
parameter: V_{GS}



6 Typ. drain-source on resistance

$R_{DS(on)}=f(I_D)$; $T_j=25$ °C

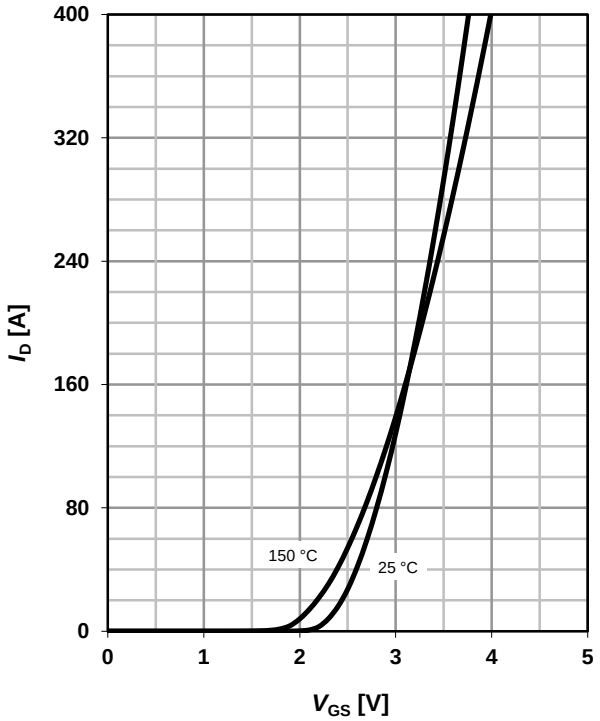
parameter: V_{GS}



7 Typ. transfer characteristics

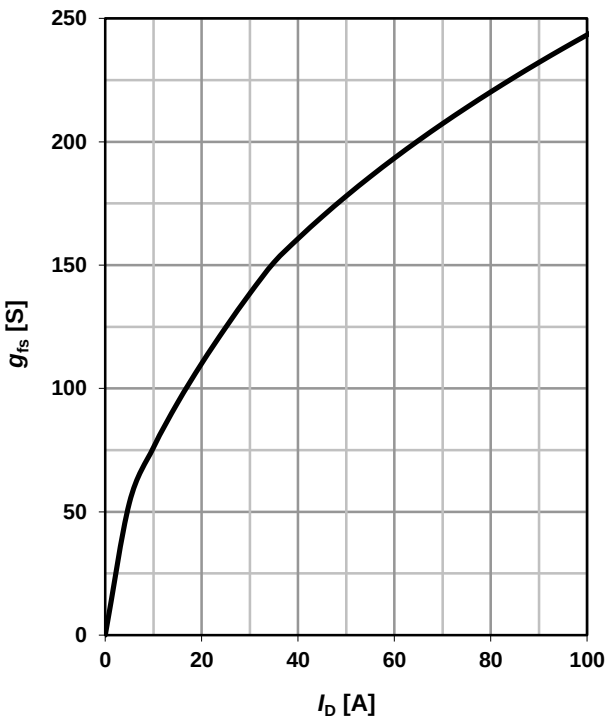
$I_D=f(V_{GS})$; $|V_{DS}|>2|I_D|R_{DS(on)max}$

parameter: T_j



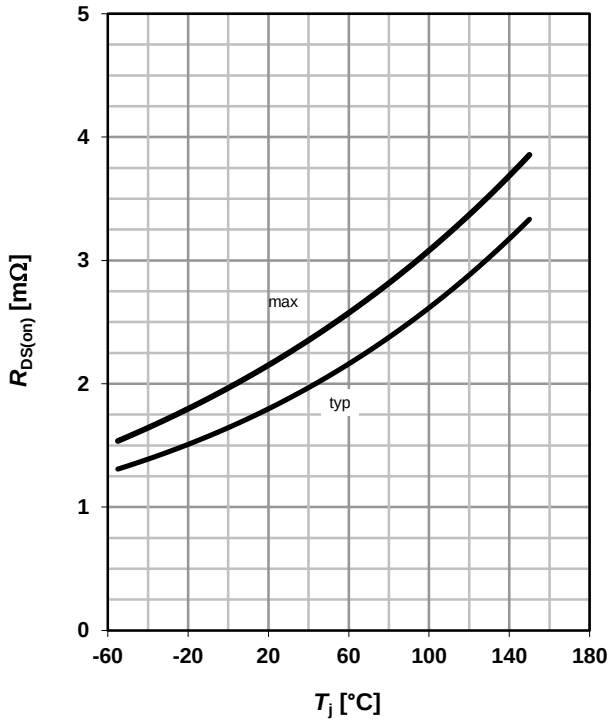
8 Typ. forward transconductance

$g_{fs}=f(I_D)$; $T_j=25$ °C



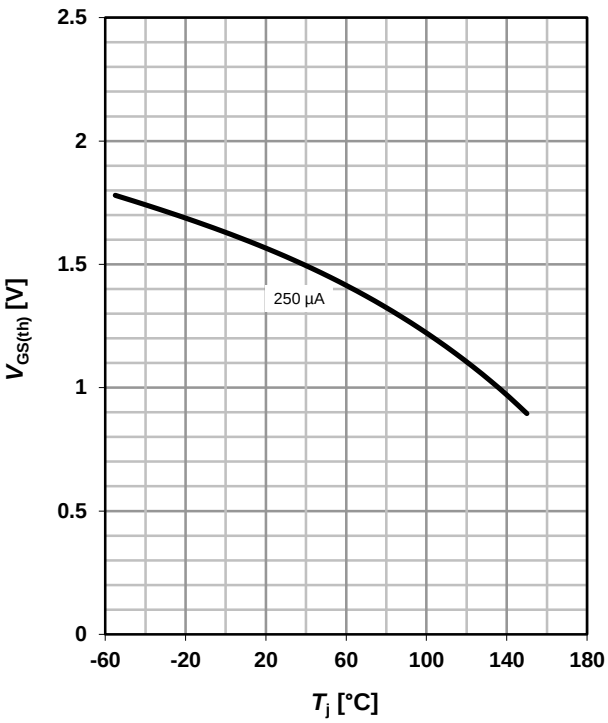
9 Drain-source on-state resistance

$R_{DS(on)}=f(T_j)$; $I_D=50$ A; $V_{GS}=10$ V



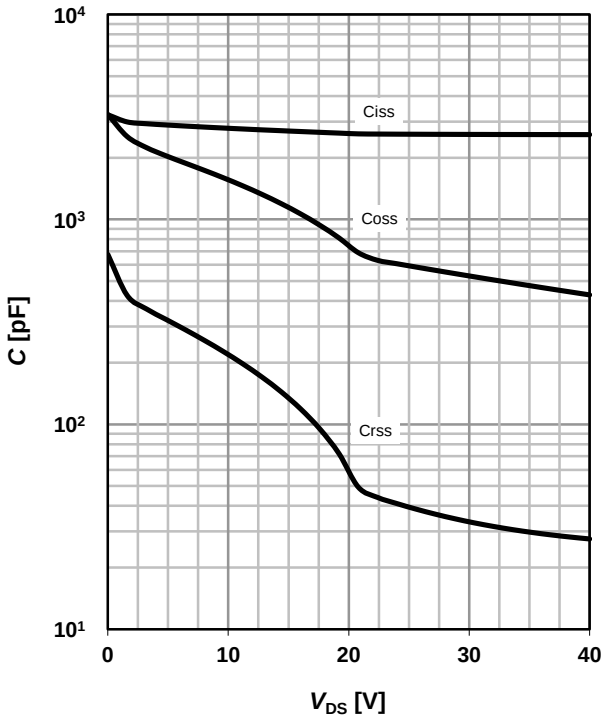
10 Typ. gate threshold voltage

$V_{GS(th)}=f(T_j)$; $V_{GS}=V_{DS}$; $I_D=250$ µA



11 Typ. capacitances

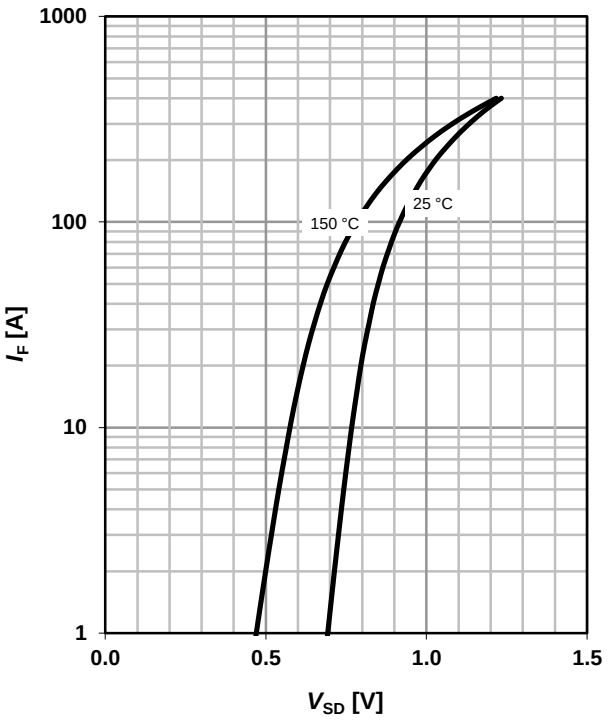
$C=f(V_{DS})$; $V_{GS}=0$ V; $f=1$ MHz



12 Forward characteristics of reverse diode

$I_F=f(V_{SD})$

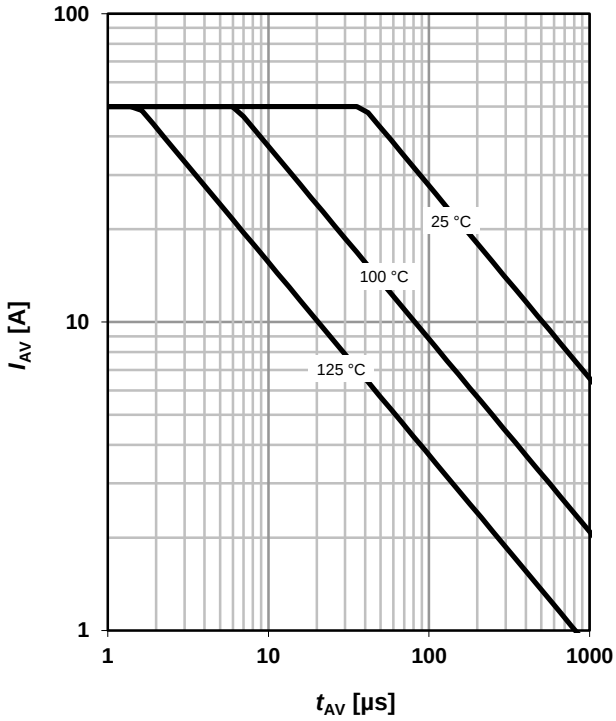
parameter: T_j



13 Avalanche characteristics

I_{AS}=f(t_{AV}); R_{GS}=25 Ω

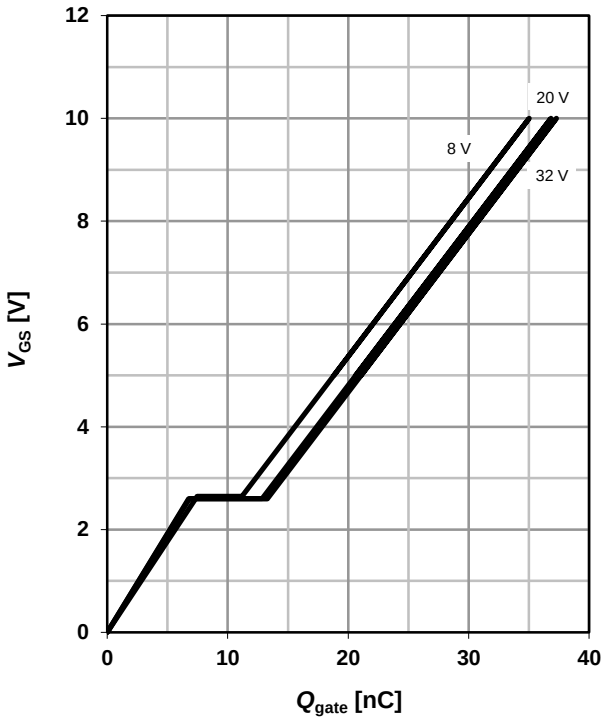
parameter: $T_{j(start)}$



14 Typ. gate charge

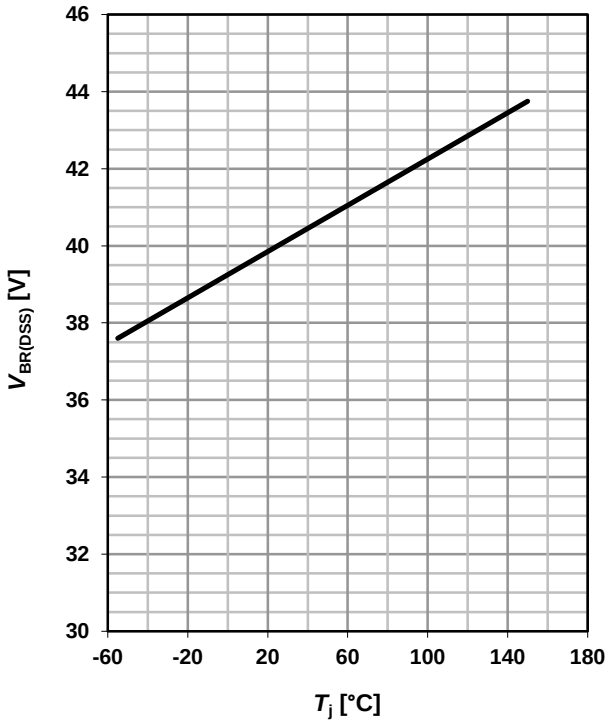
V_{GS}=f(Q_{gate}); I_D=50 A pulsed

parameter: V_{DD}

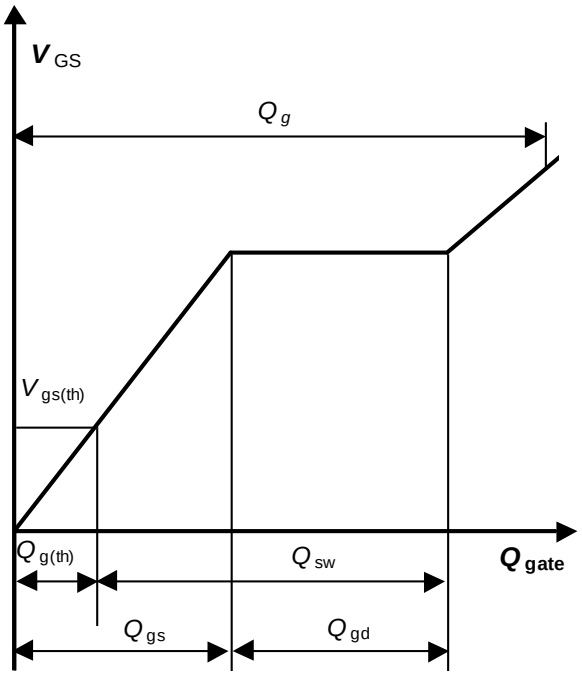


15 Drain-source breakdown voltage

$V_{BR(DSS)}$=f(T_j); I_D=1 mA

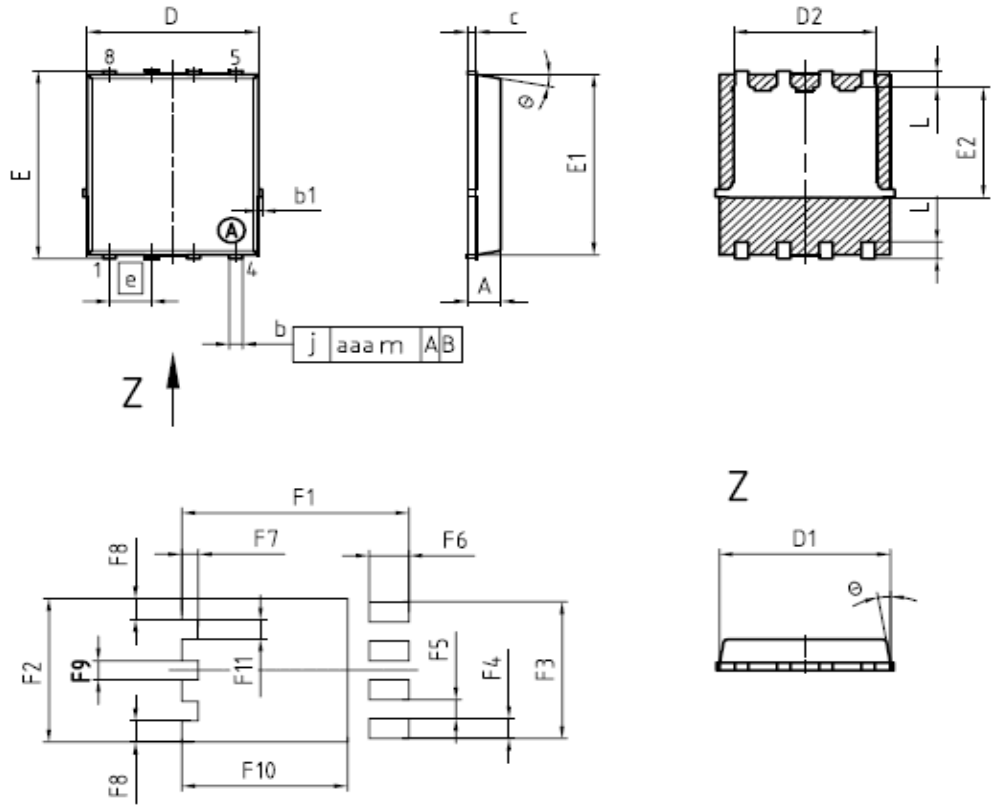


16 Gate charge waveforms



Package Outline **PG-TDSON-8**

PG-TDSON-8: Outline



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0,90	1,10	0,035	0,043
b	0,34	0,54	0,013	0,021
b1	0,02	0,22	0,001	0,008
c	0.15	0.35	0.006	0.014
D=D1	4.95	5.35	0.195	0.211
D2	4,20	4.40	0.165	0.173
E	5,95	6,35	0,234	0,250
E1	5,70	6,10	0,224	0,240
E2	3,40	3,80	0,134	0,150
e	1,27		0,050	
N	8		8	
L	0,45	0,65	0,018	0,026
ϴ	8,5°	11,5°	8,5°	11,5°
aaa	0,25		0,010	
eee	0,05		0,002	
F1	6,75	6,95	0,266	0,274
F2	4.60	4.80	0.181	0.189
F3	4.36	4.56	0.172	0.180
F4	0.55	0.75	0.022	0.030
F5	0.52	0.72	0.020	0.028
F6	1,10	1,30	0,043	0,051
F7	0,40	0,60	0,016	0,024
F8	0,60	0,80	0,024	0,031
F9	0.53	0.73	0.021	0.029
F10	4.90	5.10	0.193	0.201
F11	0.53	0.73	0.021	0.029

DOCUMENT NO.
Z8B00003332

SCALE 0 2.5 0 2.5 5mm

EUROPEAN PROJECTION

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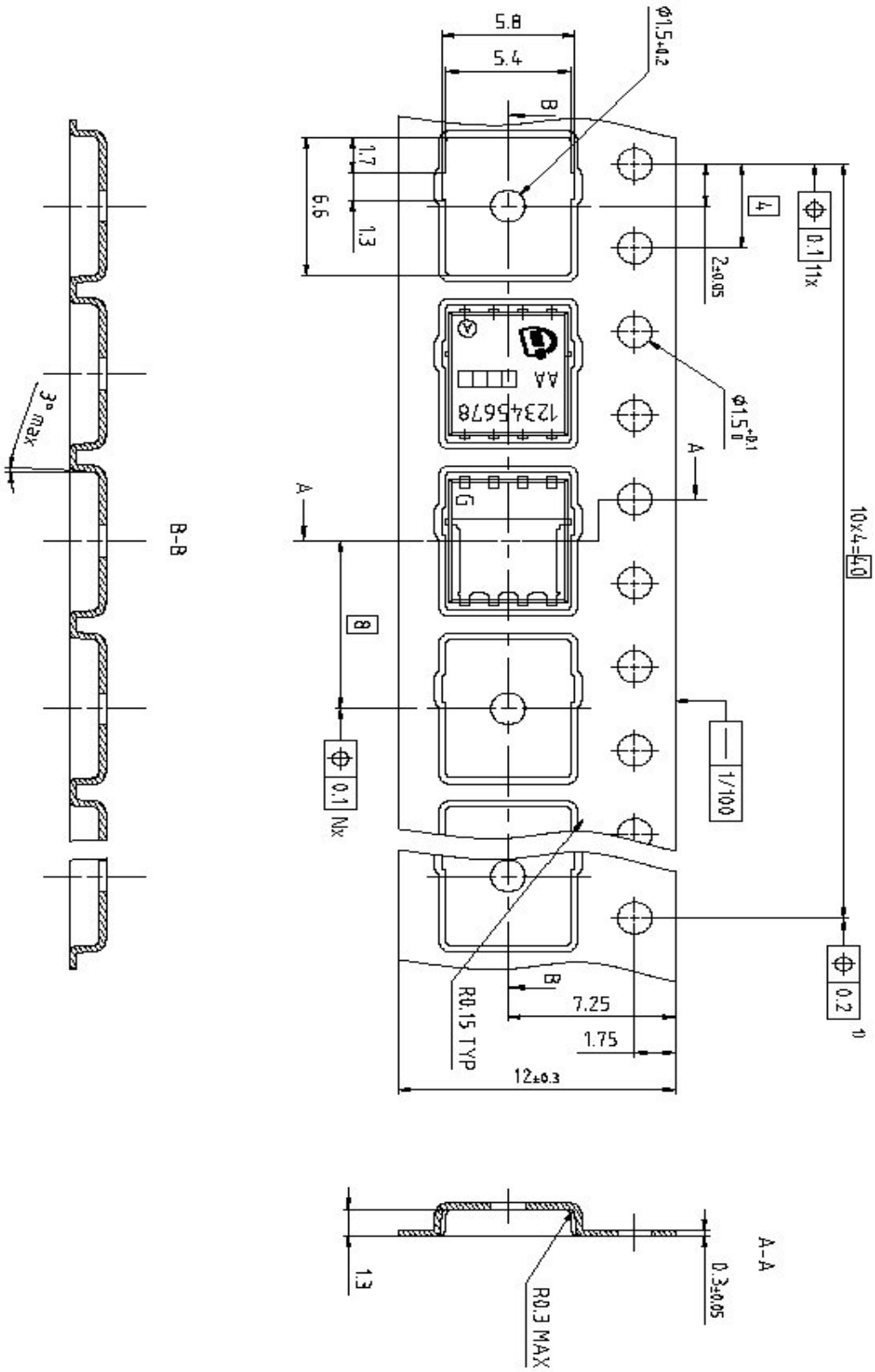
REVISION
03

Package Outline

PG-TDSON-8: Tape



Dimensions in mm

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